

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/791,809	TAKIGUCHI, HIROSH	I
Examiner	Art Unit	
Shih-wen Hsieh	2861	

	SEAR	CHED	
Class	Subclass	Date	Examiner
347	updated	8/2/2006	swh
424	490	8/2/2006	SWH
425	5,6,456	8/2/2006	swh
264	7,9 .	8/2/2006	swh

INT	ERFERENC	CE SEARCH	IED
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOT (INCLUDING SEARCH)		)
	DATE	EXMR
USPGPUB text search (see attached)	8/2/2006	SWH
	·	